

System Specifications

FULL VISION IC Handler H1

This handler is First Change Kit Less Model in the industry and concentrated the latest technology of YAMAHA/I-Pulse.

Feature

- High accuracy ($\pm 25 \mu\text{m}$) with vision processing
- Reduced device damaging rate and Low jamming rate due to only one time contact.
- Sharp reduction in change kit cost.
- Shorter preparation time due to change kit less
- Versatile infeed, outfeed method
- Optical function of pressure force control
- Multi-classification up to 8 categories
- Suitable for Minute device like WLCSP etc.



Specifications H1

Item	Standard	Option
Applicable devices	BGA , CSP , QFN , LCC and QFP,SOP	
Applicable package size	2.5mm ~ 20mm	2.5mm ~ 40mm
No. of IC's measured in parallel	2	
Pitch between sockets	60mm ~ 80mm	50 ~ 80mm
Contact method	Drop-free pressure contact method	
Alignment of devices	Correction of image recognition position	
Measurement temperature	Ordinary temperature	+50 ~ +125 ± 3 Hot plate type
Test head area	Depth from the testing center: 550mm, height: 975mm	
Device infeed method	1 unit of auto tray	
Device outfeed method	2 units of auto tray	
No. of categories	2	Additional 6, up to 8
Tray capacity	H 330mm x 2 units	1 unit of 300mm type, 1 unit of 150mm type, single placement x 6 step racks elevator
Tray size	Adjustable within the range of W(120~155mm) x L(280~335mm)xH(4~8mm) with JEDEC as the base	
Index time	0.5 seconds at shortest	
Throughput	UP to 3,600 UPH (ordinary temperature, 2pcs in parallel measurement)	
Dimensions	W1650mm×D1530mm×H1800 (excluding tower light)	
Weight	1900kg	

About this system, please contact us.

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